

Notice of References Cited	Application/Control No. 10/598,961		Applicant(s)/Patent Under Reexamination WATANABE ET AL.	
	Examiner Savitri Mulpuri		Art Unit 2812	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,122,416	10-2006	Nevin et al.	438/221
*	B	US-6,573,154	06-2003	Sridhar et al.	438/430
*	C	US-4,666,556	05-1987	Fulton et al.	438/431
*	D	US-2004/0018696	01-2004	Wieczorek et al.	438/431
*	E	US-2004/0248373	12-2004	Park, Geon-Ook	438/424
*	F	US-2003/0224580	12-2003	Huang et al.	438/435
*	G	US-4,571,819	02-1986	Rogers et al.	438/430
*	H	US-4,656,497	04-1987	Rogers et al.	257/397
*	I	US-2003/0216006	11-2003	Li et al.	438/424
*	J	US-2005/0221557	10-2005	Wang et al.	438/243
*	K	US-6,881,646	04-2005	Ishitsuka et al.	438/424
*	L	US-7,183,226	02-2007	Lee et al.	438/749
*	M	US-6,890,833	05-2005	Belyansky et al.	438/426

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.